N-Channel Power MOSFET 0.98 Ω , 600 Volts

Features

- Low ON Resistance
- Low Gate Charge
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

- Adapter (Notebook, Printer, Gaming)
- LCD Panel Power
- Lighting Ballasts

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	NDF06N60Z	NDP06N60Z	Unit
Drain-to-Source Voltage	V _{DSS}	600 (Note 1)		V
Continuous Drain Current	I _D	6.0 (Note 2)		Α
Continuous Drain Current T _A = 100°C	I _D	3.8 (Note 2)		Α
Pulsed Drain Current, V _{GS} @ 10 V	I _{DM}	20 (Note 2)		Α
Power Dissipation (Note 1)	P_{D}	31	113	W
Gate-to-Source Voltage	V _{GS}	±3	30	V
Single Pulse Avalanche Energy, L = 6.3 mH, I _D = 6.0 A	E _{AS}	113		mJ
ESD (HBM) (JESD 22-114-B)	V _{esd}	3000		٧
RMS Isolation Voltage (t = 0.3 sec., R.H. \leq 30%, T _A = 25°C) (Figure 13)	V _{ISO}	4500	-	V
Peak Diode Recovery	dv/dt	4.5 (N	ote 3)	V/ns
Continuous Source Current (Body Diode)	I _S	6.0		Α
Maximum Temperature for Soldering Leads, 0.063" (1.6 mm) from Case for 10 s Package Body for 10 s	T _L T _{PKG}	300 260		°C
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150		°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

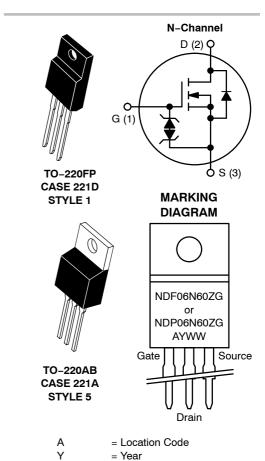
- 1. Surface mounted on FR4 board using 1" sq. pad size, 1 oz cu
- 2. Limited by maximum junction temperature
- 3. $I_{SD} = 6.0 \text{ A}$, $di/dt \le 100 \text{ A}/\mu s$, $V_{DD} \le BV_{DSS}$, $T_J = +150 ^{\circ} C$



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V _{DSS}	R _{DS(ON)} (TYP) @ 3 A		
600 V	0.98 Ω		



ORDERING INFORMATION

Work WeekPb-Free Package

WW

Device	Package	Shipping	
NDF06N60ZG	TO-220FP	50 Units/Rail	
NDP06N60ZG	TO-220AB	In Development	

THERMAL RESISTANCE

Parameter		NDF06N60Z	NDP06N60Z	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	4.0	1.1	°C/W
Junction-to-Ambient Steady State (Note 4)		50	50	

Characteristic	Test Conditions		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS					•	•	•
Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$		BV _{DSS}	600			V
Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 1 mA		$\Delta BV_{DSS}/ \ \Delta T_{J}$		0.6		V/°C
Drain-to-Source Leakage Current		25°C	I _{DSS}			1	μΑ
	V _{DS} = 600 V, V _{GS} = 0 V	150°C				50	
Gate-to-Source Forward Leakage	V _{GS} = ±20 V		I _{GSS}			±10	μΑ
ON CHARACTERISTICS (Note 5)					•	•	
Static Drain-to-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 3.0 \text{ A}$	A	R _{DS(on)}		0.98	1.2	Ω
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu$	А	V _{GS(th)}	3.0		4.5	V
Forward Transconductance	V _{DS} = 15 V, I _D = 3.0 A	A	9FS		5.0		S
OYNAMIC CHARACTERISTICS					•	•	•
Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		C _{iss}		923		pF
Output Capacitance			C _{oss}		106		
Reverse Transfer Capacitance			C _{rss}		23		
Total Gate Charge	$V_{DD} = 300 \text{ V}, I_D = 6.0 \text{ A},$ $V_{GS} = 10 \text{ V}$		Qg		31		nC
Gate-to-Source Charge			Q _{gs}		6.3		
Gate-to-Drain ("Miller") Charge	VGS = 10 V		Q _{gd}		17		1
Gate Resistance			R_g		3.2		Ω
RESISTIVE SWITCHING CHARACTERI	STICS				-	•	•
Turn-On Delay Time			t _{d(on)}		13		ns
Rise Time	V_{DD} = 300 V, I_{D} = 6.0 A, V_{GS} = 10 V, R_{G} = 5 Ω		t _r		17		
Turn-Off Delay Time			t _{d(off)}		30		
Fall Time			t _f		28		
OURCE-DRAIN DIODE CHARACTER	ISTICS (T _C = 25°C unless oth	erwise note	ed)				
Diode Forward Voltage	I _S = 6.0 A, V _{GS} = 0 V		V_{SD}			1.6	V
Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 30 V I _S = 6.0 A, di/dt = 100 A/μs		t _{rr}		338		ns
Reverse Recovery Charge			Q _{rr}		2.0		μС

Insertion mounted
 Pulse Width ≤ 380 μs, Duty Cycle ≤ 2%.

TYPICAL CHARACTERISTICS

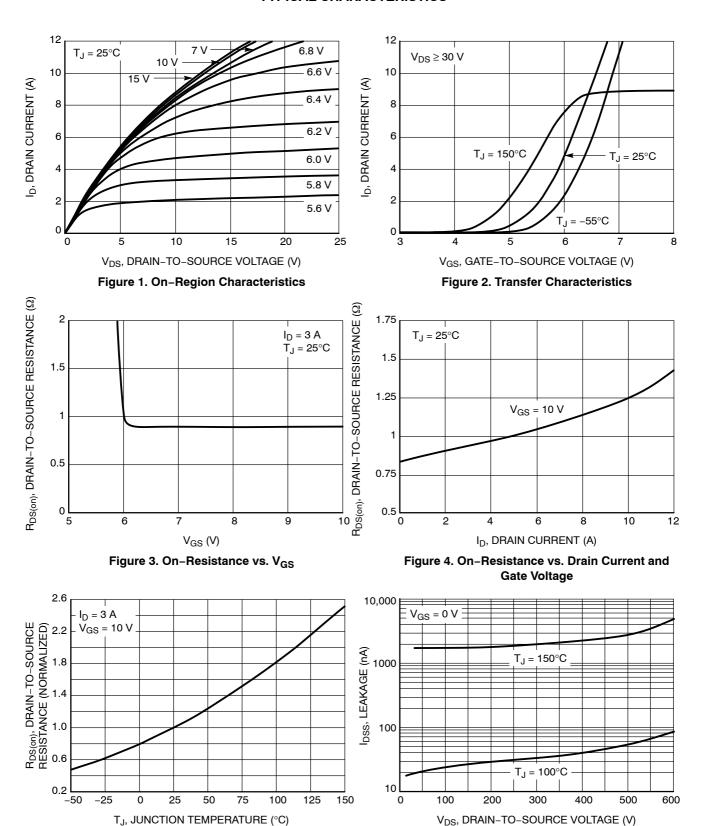


Figure 6. Drain-to-Source Leakage Current

vs. Voltage

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

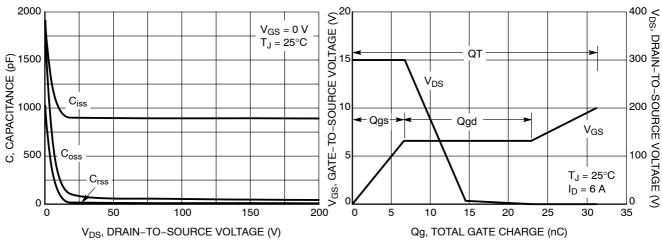


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

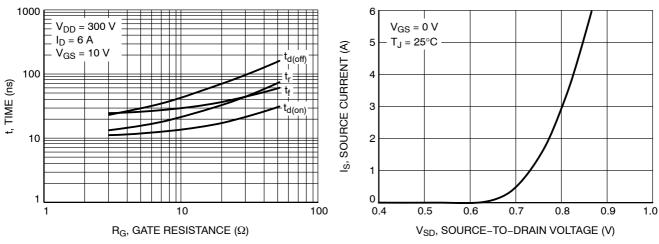


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

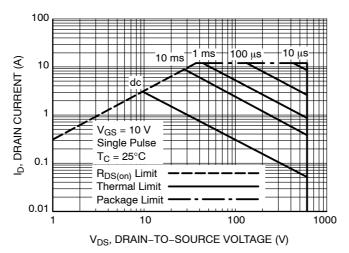


Figure 11. Maximum Rated Forward Biased Safe Operating Area for NDF06N60Z

TYPICAL CHARACTERISTICS

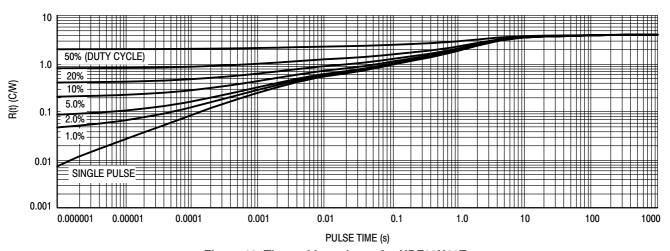


Figure 12. Thermal Impedance for NDF06N60Z

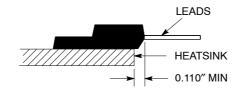


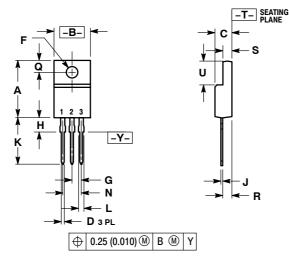
Figure 13. Mounting Position for Isolation Test

Measurement made between leads and heatsink with all leads shorted together.

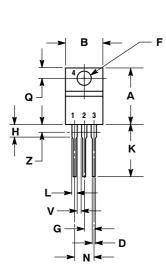
PACKAGE DIMENSIONS

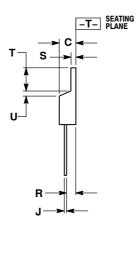
TO-220 FULLPAK CASE 221D-03

ISSUE J



TO-220AB CASE 221A-09 **ISSUE AE**





NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH 221D-01 THRU 221D-02 OBSOLETE, NEW 3. STANDARD 221D-03.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	0.617	0.635	15.67	16.12	
В	0.392	0.419	9.96	10.63	
С	0.177	0.193	4.50	4.90	
D	0.024	0.039	0.60	1.00	
F	0.116	0.129	2.95	3.28	
G	0.100	BSC	2.54 BSC		
Н	0.118	0.135	3.00	3.43	
J	0.018	0.025	0.45	0.63	
K	0.503	0.541	12.78	13.73	
L	0.048	0.058	1.23	1.47	
N	0.200 BSC		5.08 BSC		
Q	0.122	0.138	3.10	3.50	
R	0.099	0.117	2.51	2.96	
S	0.092	0.113	2.34	2.87	
U	0.239	0.271	6.06	6.88	

STYLE 1: PIN 1. GATE

DRAIN 2

- DIMENSIONING AND TOLERANCING PER ANSI
 - CONTROLLING DIMENSION: INCH
- DIMENSION Z DEFINES A ZONE WHERE ALL **BODY AND LEAD IRREGULARITIES ARE** ALLOWED.

	INCHES		MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.570	0.620	14.48	15.75
В	0.380	0.405	9.66	10.28
С	0.160	0.190	4.07	4.82
D	0.025	0.035	0.64	0.88
F	0.142	0.161	3.61	4.09
G	0.095	0.105	2.42	2.66
Н	0.110	0.155	2.80	3.93
J	0.014	0.025	0.36	0.64
K	0.500	0.562	12.70	14.27
L	0.045	0.060	1.15	1.52
N	0.190	0.210	4.83	5.33
Q	0.100	0.120	2.54	3.04
R	0.080	0.110	2.04	2.79
S	0.045	0.055	1.15	1.39
T	0.235	0.255	5.97	6.47
U	0.000	0.050	0.00	1.27
٧	0.045		1.15	
Z		0.080		2.04

STYLE 5: PIN 1.

GATE DRAIN 2.

SOURCE DRAIN

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